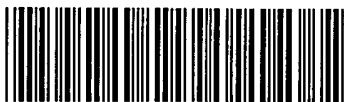


# Search Notes



Application No.

10/608,263

Examiner

Bernard E Souw

Applicant(s)

HASHIMOTO ET AL.

Art Unit

2881

## SEARCHED

Class	Subclass	Date	Examiner
250	282	12/03/03	BES
1	292		
1	290		
280	281		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
(ion trap) (mass spectrometer) + gas introduction		
(inlet or orifice or hole or opening or port) +	12/01/01	BES
(AC or RF or supple- ment) voltage near (bond band or frequency scan) var or + dissociate		
+ (endcap or ring) electrode		